

**Search Notes**

Application/Control No.

10/594,282

Examiner

Sin J. Lee

Applicant(s)/Patent under  
Reexamination

ISHII ET AL.

Art Unit

1795

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EIC structure searches were reviewed again.	12/20/2009	SJL